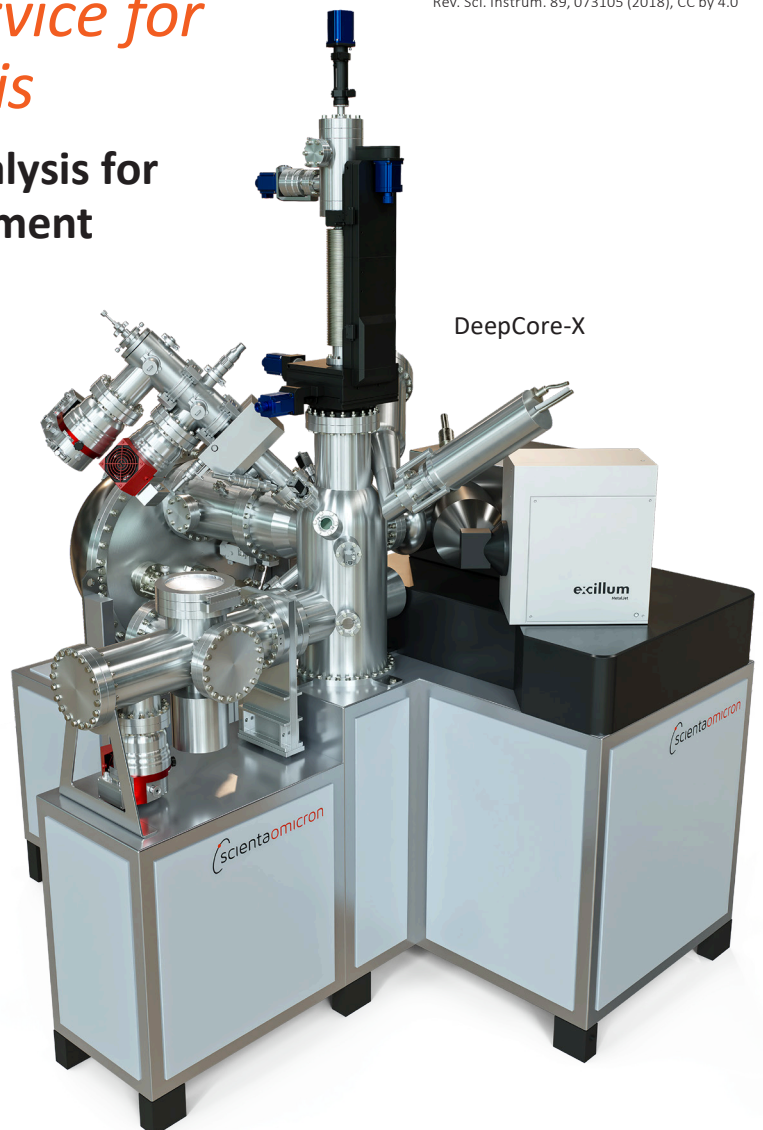


Unlock Deep Insights: XPS and HAXPES as-a-Service for Advanced Surface Analysis

**Non-destructive, bulk-sensitive analysis for
cutting-edge research and development**

Gain access to the unparalleled power of high energy XPS (HAXPES) without the need for capital investment. We deliver cutting-edge material analysis tailored to your needs, offering precision, speed, and flexibility.

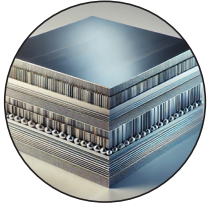
We specialize in delivering XPS and advanced Deep HAXPES measurements to academic and industrial laboratories. Our service integrates state-of-the-art technology, innovative methodologies, and expert support to help you uncover new insights into material interfaces and properties.



Unique information by Deep HAXPES

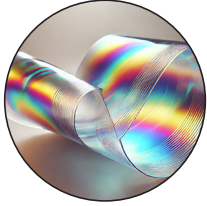
- Non-destructive & bulk-sensitive depth profiling
- Access to buried interfaces (up to 50 nm below the material surface)
- Access to sub-surface chemical and electronic material properties
- Operando measurement possibilities

Applications



Buried Layers and Interfaces

Analyze buried interfaces in semiconductors, display technologies and multilayer coatings with precision.



Coatings and Thin Films

Non-destructive analysis of chemical gradients and interdiffusion at material interfaces.



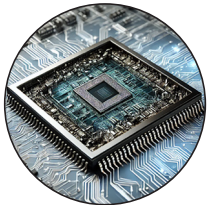
Corrosion

Understand degradation processes to improve the durability of metal alloys and coatings.



Materials for Energy Applications

Investigate band alignment and material degradation in batteries and photovoltaic systems.



Semiconductor Heterostructure Devices

Explore interface chemistry and electronic properties in advanced semiconductor materials.

The scope and details of the measurements and report are subject to agreement.

Core Features

- Standard and high energy XPS (Deep HAXPES)
- Non-destructive and bulk-sensitive analysis
- Elemental characterization by XPS and Deep HAXPES
- Chemical characterization of the elemental composition up to 50 nm below the sample surface

Benefits

- Quick turnaround time for results
- Comprehensive analysis reports with metadata
- Flexible measurement time agreements

Add-Ons

- Advanced analysis services upon request